

Notice of References Cited	Application/Control No. 09/887,781	Applicant(s)/Patent Under Reexamination ANN ET AL.
	Examiner Tan Dean D. Nguyen	Art Unit 3689

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,256,773	07-2001	Bowman-Amuah, Michel K.	717/121
*	B	US-2002/0069102	06-2002	Vellante et al.	705/10
*	C	US-2002/0133368	09-2002	Strutt et al.	705/1
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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